Numerical Studies of Electro-Osmotic flows of Viscoelastic fluids

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Introduction

- Electro-Osmotic Flow (EOF): Theory
- 2 Governing Equations
 - EOF of Viscoelastic Fluid
 - Electrokinetics

3 Numerical Solutions

- Channel flows
- Complex geometries

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Electro-Osmotic Flow (EOF)

Surface charge

Surface charge:

- Solution of ions
- Overall charge neutrality

Electric Double Layer (EDL):

- Mobile diffusive layer
- Immobile layer (Stern Model)
- Debye layer: $\lambda_D = \frac{1}{\kappa} = \sqrt{\frac{\epsilon k_B T}{2n_o e^2 z^2}}$

Electro-Osmotic Velocity:

- Apply an external potential Electric force $\mathbf{F} = \rho_e \mathbf{E}$
- Viscous forces drag the solution.



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Electro-Osmotic Flows (EOF)

Aplications

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 micro flow injection analysis, microfluidic chromatography, microreactors, microenergy, microelectronic cooling systems and micro-mixing.

Interesting Flow Instabilities:

• Newtonian fluids^[1].

• Viscoelastic fluids^[2].

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Outflow v Dyed Fluid v Hoating Reservoir

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Mass & Momentum Conservation

Mass Conservation:

 $\nabla \cdot \mathbf{u} = 0$

Momentum Conservation:

$$\rho \frac{D\mathbf{u}}{Dt} = -\nabla p + \nabla \cdot \boldsymbol{\tau} - \rho_e \nabla \left(\phi + \psi\right)$$

Constitutive Equation:

$$f(\tau_{kk})\boldsymbol{\tau} + \lambda \boldsymbol{\tau} = 2\eta \mathbf{D}$$
 $\boldsymbol{\nabla} = \frac{D\boldsymbol{\tau}}{Dt} - \boldsymbol{\tau} \cdot \boldsymbol{\nabla} \mathbf{u} - \boldsymbol{\nabla} \mathbf{u}^T \cdot \boldsymbol{\tau}$

Phan-Thien & Tanner (PTT) $f(au_{kk}) = 1 + rac{arepsilon\lambda}{\eta} au_{kk}$

Upper Convected Maxwell (UCM) $\varepsilon = 0 \ \Rightarrow \ f(\tau_{kk}) = 1$

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Electric Body Force

Mass Conservation:

 $\nabla \cdot \mathbf{u} = 0$

Momentum Conservation:

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Nernts-Plankt Equations

$$\nabla^2 \phi = 0$$

$$\nabla^2 \psi = -\frac{ez}{\epsilon} (n^+ - n^-)$$

$$\rho_e = ez (n^+ - n^-)$$

$$\frac{\partial n^{\pm}}{\partial t} + \mathbf{u} \cdot \nabla n^{\pm} = \nabla \cdot (D^{\pm} \nabla n^{\pm}) \pm \nabla \cdot \left[D^{\pm} n^{\pm} \frac{ez}{k_B T} \nabla \Phi \right]$$

Nernts-Plankt Equations (NP)

Mass Conservation:

 $\nabla \cdot \mathbf{u} = 0$

Momentum Conservation:

$$\rho \frac{D\mathbf{u}}{Dt} = -\nabla p + \nabla \cdot \boldsymbol{\tau} - \boldsymbol{\rho}_{e} \nabla \left(\boldsymbol{\phi} + \boldsymbol{\psi} \right)$$

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Poisson-Boltzmann Equations (PB)

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Poisson-Boltzmann Equations (PB)

$$\nabla^2 \phi = 0$$
$$\nabla^2 \psi = -\frac{2n_o ez}{\epsilon} \sinh\left(\frac{ez}{k_B T}\psi\right)$$
$$\rho_e = 2n_o ez \sinh\left(\frac{ez}{k_B T}\psi\right)$$

Numerical Method

Finite Volume Method^[1]

- Structured, collocated and non-orthogonal meshes.
- Discretization (formally 2nd order)
 - Diffusive terms: central differences (CDS)
 - Advective terms, high resolution scheme: CUBISTA^[2]
- Dependent variables evaluated at cell centers;
- Special formulations for cell-face velocities and stresses;
- Log-conformation for the extra-stress tensor^[3].
- $\sinh \text{ linearization}^{[4]}: \sinh(X) = \sinh(X)^n + (X^{n-1} X^n) \cosh(X)^n$

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Channel Flow - Computational Domain



Computational meshes

	nº cells	$\triangle x_{min}$	$\Delta y_{min} \times 10^{-4}$	
M1	1800	0.2	8	
M2	3600	0.2	4	
M3	7200	0.2	2	

Channel Flow - Mesh convergence



Computational meshes

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Channel Flow - Mesh convergence



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Numerical Solutions Channel Flow - NP/PB equations



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Numerical Solutions Channel Flow - NP/PB equations



Analytical Solution

$$\frac{u(y)}{u_{sh_0}} = \frac{1}{\beta} \left(1 - \frac{\sinh(\bar{\kappa}y)}{\cosh(\bar{\kappa})} - (1 - \beta) \left[\Omega(1) - \frac{\sinh(\bar{\kappa}y)}{\cosh(\bar{\kappa})} \Omega(y) \right] \right) \qquad \beta = \frac{\eta_s}{\eta_0} = \frac{\eta_s}{\eta_p + \eta_s}$$

$$D(y) = \sum_{n=0}^{\infty} \left[\frac{\left(\frac{1}{3}\right)_n \left(\frac{1}{2}\right)_n \left(\frac{2}{3}\right)_n}{\left(\frac{3}{2}\right)_n \left(\frac{3}{2}\right)_n} \frac{\left(-\frac{27}{2}\beta\varepsilon De_{\kappa_0}^2 \left(\frac{\sinh(\bar{\kappa}y)}{\cosh(\bar{\kappa})}\right)^2\right)^n}{n!} \right] \qquad De_{\kappa_0} = u_{sh_0}\kappa\lambda$$

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AERC 2010, Gothenburg, Sweden

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Channel Flow - NP/PB equations and Analytical solution (PTT model)



$$\Omega(y) = \sum_{n=0}^{\infty} \left\lfloor \frac{\left(\frac{1}{3}\right)_n \left(\frac{1}{2}\right)_n \left(\frac{2}{3}\right)_n}{\left(\frac{3}{2}\right)_n \left(\frac{3}{2}\right)_n} \frac{\left(-\frac{27}{2}\beta\varepsilon De_{\kappa_0}^2 \left(\frac{\sinh(\bar{\kappa}y)}{\cosh(\bar{\kappa})}\right)^2\right)}{n!}\right)}{n!}\right\rfloor$$

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Cross Slot: geometry



Computational mesh (same refinement of M1)

n [♀] cells		
12801	4	4

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Cross Slot: meshes



Cross Slot: meshes



Computational mesh (same refinement of M1)

	nº cells	$\Delta x_{min} \times 10^{-4}$	$\Delta y_{min} \times 10^{-4}$
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Pure newtonian EOF: external potential



Numerical Solutions Pressure profiles in the Cross-slot



Numerical Solutions Effect of Debye Layer size ($\kappa H = 100$)



Numerical Solutions Effect of Debye Layer size ($\kappa H = 50$)



Numerical Solutions Effect of Debye Layer size ($\kappa H = 20$)



Numerical Solutions Effect of Debye Layer size ($\kappa H = 10$)



Numerical Solutions Effect of Debye Layer size ($\kappa H = 5$)



Creeping flow of pure Viscoelastic EOF using UCM ($\varepsilon = 0$)

$De_{\kappa} = \lambda U \kappa$	$De_H = \frac{\lambda U}{H}$
0	0
1	0.01
2	0.02
3	0.03
4	0.04
4.88	0.0488
4.9	0.049
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Stability Maps: $De.vs.\kappa H$



Conclusions

Numerical solutions

- Excellent agreement with analitical solutions;
- Sharp refinement near the EDL (Alternative: Viscoelastic

Helmholtz-Smoluchowski Velocity at the wall (Slip velocity)^[1]);

Elastic instabilities

- Elastic instabilities present in the viscoelastic EOF flow in Cross-Slot geometry;
- The critical Deborah number increased with Debye layer relative size (κH);
- No steady assymetric flow ^[2] were obtained, rounded corners are needed;

 $^{1]}$ Park and Lee, JCIS (2009) $^{[2]}$ Poole, Alves and Oliveira, PRL (2007)

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Thanks!

Questions?

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